

# Wednesday Afternoon, October 21, 2015

## Exhibitor Technology Spotlight

Room: Hall 1 - Session EW-WeA

## Exhibitor Technology Spotlight Session

Moderator: Dennis Sollon, Kurt J. Lesker

4:00pm EW-WeA6 Title Innovative Raman imaging, *Tim Prusnick*, RENISHAW, INC.

Renishaw's inVia is the world leader in confocal Raman spectroscopy. The inVia offers a wide range of imaging techniques that allow the user to choose the optimal solution for a particular sample type. Renishaw has partnered with other instrument vendors to combine atomic force microscopy (AFM) and scanning electron microscopy (SEM) to provide Raman analysis from the same point on the sample. The SEM Structural and Chemical Analyzer (SEM-SCA) combines both SEM and Raman techniques into one system, so that users can take full advantage of the high spatial resolution, large depth of field and high contrast afforded by the SEM, and the chemical information revealed by Raman. The Atomic Force Microscope (AFM) combine AFM and Raman to allow users to simultaneously acquire data from the same point on the sample without having to move it. This ensures that your data are consistent, even if your sample is changing with time.

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